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This multivibrator features a negative-transition-triggered input and a positive-transition-triggered input either of which can be used as an inhibit input. Pulse triggering occurs at a particular voltage level and is not directly related to the transition time of the input pulse. Schmitt-trigger input circuitry (TTL hysteresis) for B input allows jitter-free triggering from inputs with transition rates as slow as 1V/s, providing the circuit with excellent noise immunity of typically 1.2V. A high immunity to V_{CC} noise of typically 1.5V is also provided by internal latching circuitry. Once fired, the outputs are independent of further transitions of the A and B inputs and are a function of the timing components, or the output pulses can be terminated by the overriding clear. Input pulses may be of any duration relative to the output pulse. Output rise and fall times are TTL compatible and independent of pulse length.

Typical triggering and clearing sequence are illustrated as a part of the switching characteristics waveforms. Pulse width stability is achieved through internal compensation and is virtually independent of V_{CC} and temperature.

In most applications, pulse stability will only be limited by the accuracy of external timing components. Jitter-free operation is maintained over the full temperature and V_{CC} range for more than six decades of timing capacitance (10pF to 10µF) and more than one decade of timing resistance (2k Ω to 100k Ω).

Throughout these ranges, pulse width is defined by the relationship: tw/out/=Cext+Rext+1n.2.

INFUNCTION TABLE

	Inputs		Out	puts
Clear	A	В	Q	Q
Ĺ	×	×	L	н
×	Н	×	L	Н
×	×	L	L	н
н	L	1	Л_	
н	1	H		
1	L	н		

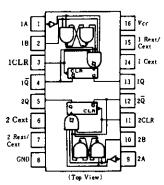
H; high level, L; low level, X; irrelevant. 1: Transition from high to low level.

- t; Transition from low to high level.
- ∴; one high-level pulse.
- Lr; one low-level pulse.

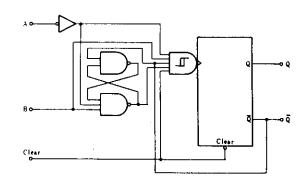
PRECOMMENDED OPERATING CONDITIONS

Item		Symbol	min	typ	max	Unit	
Rate of rise or fall	Schmitt input, B	dV/dt	1	-	_	V/s	
of input pulse logic input, A		av/at	1			V/μs	
Input pulse width	A or B	lw(in)	40	_	_		
	Clear	łu(ciear)	40	-		ns	
Setup time		lm	15		_	ns	
External timing resistance		Reze	1.4	_	100	kΩ	
External timing capacitance		Cexi	0	_	1,000	μF	
Duty cycle	$R\tau = 2k\Omega$			_	50	- %	
	$R\tau = 100 \text{k} \Omega$	ĺ	_	_	90		

EPIN ARRANGEMENT



■BLOCK DIAGRAM (½)



ELECTRICAL CHARACTERISTICS ($Ta = -20 \sim +75^{\circ}C$)

Item		Symbol	Test Conditions		min	typ*	max	Unit
		V_T^+	$V_{CC} = 4.75 \text{V}$		E. 11*	1.0	2.0	V
Threshold voltage	A	$V\tau^-$	Vcc=4.75V		0.8	1.0	_	V
		V _T *	$V_{CC} = 4.75 \text{V}$		_	1.0	2.0	V
	В	Vr -	$V_{CC} = 4.75 \text{V}$	$V_{CC} = 4.75 \text{V}$				V
		Von	$V_{CC} = 4.75 \text{V}, I_{OH} = -400 \mu$	A	2.7		_	V
Output voltage				IoL = 4mA	_		0.4	v
		Vol	$V_{CC}=4.75V$	Io L = 8mA	_	_	0.5	· ·
		Iн	$V_{CC} = 5.25V, V_I = 2.7V$	·	_	_	20	μА
_	A				-		-0.4	mA
Input current	B, Clear	Iιι	$V_{CC} = 5.25 \text{V}, V_I = 0.4 \text{V}$		_		-0.8	
		Iı .	$V_{CC} = 5.25 \text{V}, V_I = 7 \text{V}$		-	_	0.1	m A
Short-circuit output current		los	$V_{CC} = 5.25$ V		-20	-	-100	mA
Supply current		rent Icc		Ouiescent	_	4.7	11	
			Vcc=5.25V Trigge			19	27	m A
Input clamp voltage		V_{IK}	$V_{CC} = 4.75 \text{V}, I_{IN} = -18 \text{mA}$		_		-1.5	V

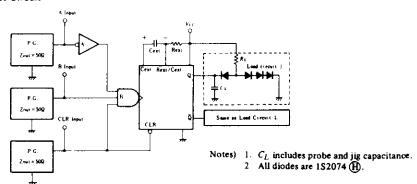
^{*} VCC=5V, Ta=25°C

ESWITCHING CHARACTERISTICS ($V_{CC}=5V$, $T_a=25^{\circ}C$)

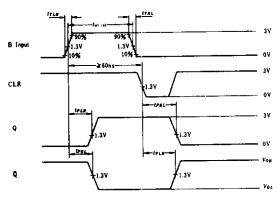
Item	Symbol	Inputs	Outputs		Test Conditions	min	typ	max	Unit
Propagation delay time		A	Q				45	70	
	tPLH	В	Q		Cest = 80pF		35	55	ns
	tpHL .	A	Q			-	50	80	
		В	Q		$R_{ext} = 2 k \Omega$		40	65	ns
	tPHL	Clear	Q	$C_L = 15pF$			35	55	ns
	<i>lpl</i> H	Clear	Q	$R_L = 2 \mathbf{k} \Omega$		-	44	65	ns
Output pulse width				7	$C_{ext} = 80 \text{pF}, R_{ext} = 2 \text{k} \Omega$	70	120	150	
		, ,			$C_{ext}=0,\ R_{ext}=2\mathrm{k}\ \Omega$	20	47	70	ns
	twomen . A or I	A or B	Q or Q		$C_{ext} = 100 \text{pF}$, $R_{ext} = 10 \text{k} \Omega$	600	670	750	1
			1		$C_{ext} = 1 \mu F$, $R_{ext} = 10 k \Omega$	6	6.7	7.5	ms

TESTING METHOD

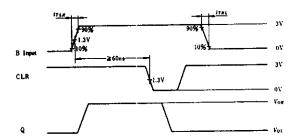
1) Test Circuit



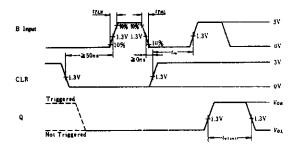




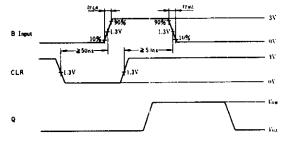
Trigger from B, then clear (A input is low).



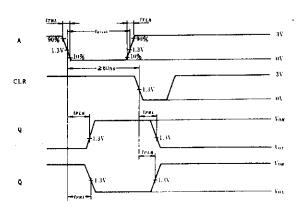
Trigger from B, then clear (A input is low).



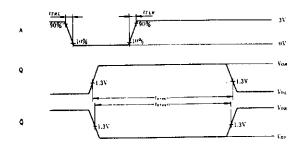
Clear overriding B, then trigger from B.



Triggering from positive transition of Clear.



Trigger from A, then clear (B input is high).

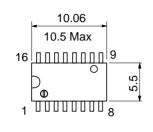


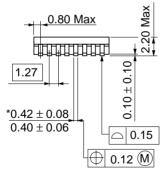
Trigger from A (B and clear inputs are high).

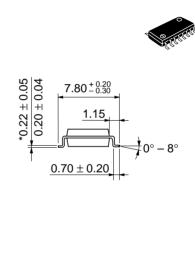
Note) Input pulse: $t_{TLH} \le 15 \text{ns}$, $t_{THL} \le 6 \text{ns}$, PRR = 1 MHz

Unit: mm 19.20 20.00 Max 16 7.40 Max 6.30 1.3 1.11 Max 7.62 5.06 Max 2.54 Min 0.51 Min $0.25^{+0.13}_{-0.05}$ 0.48 ± 0.10 2.54 ± 0.25 $0^{\circ} - 15^{\circ}$ Hitachi Code DP-16 **JEDEC** Conforms EIAJ Conforms Weight (reference value) 1.07 g

Unit: mm







*Dimension including the plating thickness
Base material dimension

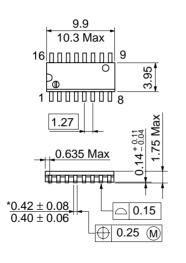
EIAJ Conforms
Weight (reference value) 0.24 g

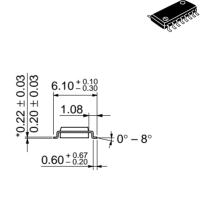
FP-16DA

Hitachi Code

JEDEC

Unit: mm





*Dimension including the plating thickness
Base material dimension

Hitachi Code	FP-16DN
JEDEC	Conforms
EIAJ	Conforms
Weight (reference value)	0.15 g

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